

A scalable model based RTL framework zamiaCAD for static analysis

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Application of high-level decision diagrams for simulation-based verification tasks

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Applications of the open source HW design framework zamiaCAD

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Jutman, Artur; Tšertov, Anton; Tšepurov, Anton; Aleksejev, Igor; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 19th EAEEIE Annual Conference : June 29-July 2, 2008, Tallinn, Estonia : formal proceedings 2008 / p. 123-128 : ill
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VHDL design debug framework based on zamiaCAD

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